

Protocol:	<b>TESTING AND ANALYSIS OF MICROSTRUCTURE</b>	<b>A1</b>
Lecturer:		

## COMPUTED TOMOGRAPHY (CT)

What type of device did we use in the exercise? .....

What is the highest acceleration voltage that can be used on our CT? .....

Determine the internal composition/content of the demonstration sample using CT:

Sample description: .....

Inside the demonstration sample (Kinder egg) there is: .....

## POWDER X-ray DIFFRACTION ANALYSIS (XRD)

Did you notice the name of the manufacturer of the XRD used? .....

The aim of the experiment is to determine the mineralogical composition of an unknown sample:

Instrument settings for the experiment (kV/mA)? .....

Macroscopic description of the sample: .....

Result of mineralogical analysis: .....

## ELECTRON MICROSCOPY (SEM)

What type of instrument did we use in the exercise? .....

What theoretical magnification can be achieved with the SEM used? .....

The aim of the experiment is to demonstrate the capabilities of SEM:

Macroscopic description of samples: .....